

Identification of dual processes using side-channels

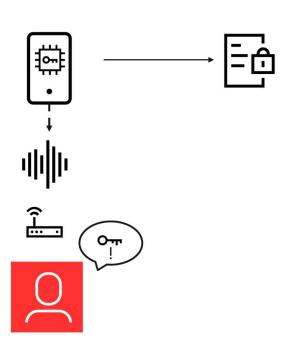
Niklas Lindskog, Ericsson Research, Lund, Sweden Jakob Sternby, Ericsson Research, Lund, Sweden Håkan Englund, Ericsson Research, Lund, Sweden

Niklas Lindskog Ericsson Research 2025-10-29

Side-channels – in a nutshell

A side-channel:

- Is a covert channel to extract information about the internal state of electronic device.
- Exists because there is a correlation between the internal state of the device and an observable information leakage.
- Leakage be component-specific or target an entire device.
- Leakage be utilized by an attacker to extract secret data, e.g., cryptographic keys
- Leakage can also be utilized to monitor the health of a device or a software process.
- Exists in many different variants
 - Logical (Memory access patterns, network traffic, etc.)
 - Physical (Power consumption, electromagnetic emissions, heat, etc.)





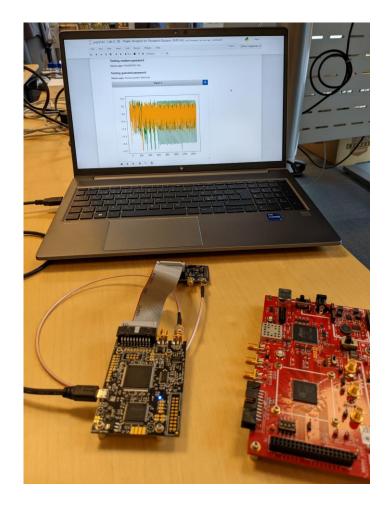
Extracting physical side-channels

- Power consumption, electromagnetic emissions, heat, acoustics etc.
- Can be measured locally by external probe or by telemetries in device.
- Power consumption
 - Measured using a resistor shunt in the VCC line.
 - Can determine fluctuations in power consumption.
 - Granularity can be weakened by capacitor.
 - Can also be measured from the "inside" by power management unit.
- Electromagnetic emissions
 - Measured using an electromagnetic probe.
 - Strength varies with power consumption.
 - Noisier but can focus on part of chip.
- Heat
 - Thermal camera
 - · Can also be measured inside device.



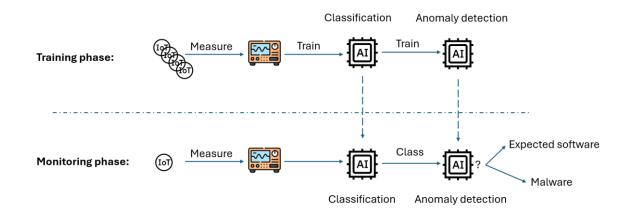
Side-channel monitoring

- Leverage covert channel to protect the device
 - Enables runtime monitoring of processes without presence on device.
 - Possible to retro-fit on existing equipment.
 - Very difficult for attackers to stay undetected in side-channel emissions.
- Almost same procedure as side-channel analysis
 - Less focused on data, more on instructions
 - Goal is to find anomalies compared to expected behavior
- Preferable to avoid repetitions one-shot analysis
 - Most attacks on cryptographic keys rely on repetition
- Can be used both as standalone solution and as complement to conventional security solutions.



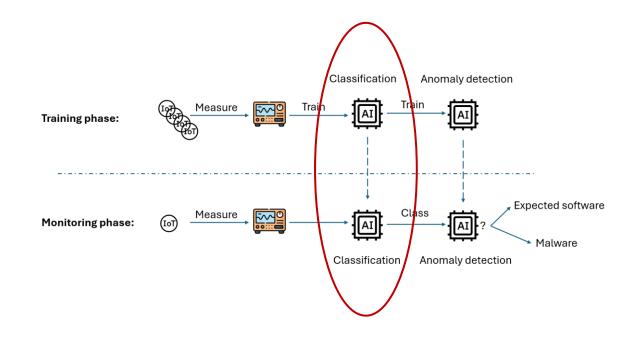
Multi-process side-channel monitoring

- What if expected behavior of device is many different simultaneous behavior?
- Process becomes twofold
 - Determine which process that is executing
 - Is the determined process executing correctly?
- Anomaly detection in presence of uncorrelated processes is studied in the existing literature
 - Classifying multi-processes is not well-studied



Multi-process side-channel monitoring

- How do we separate a side-channel measurement into multiple processes?
- Alternatives:
 - Multiple probes
 - Possible but increases complexity of monitoring
 - Create super-classes (i.e., A + B, A + C, etc.)
 - · Only possible if processes are correlated
 - Learn to separate two processes from single measurement
 - Encode processor characteristics as a part of classification?
 - Our approach



Research questions

We want to determine

- Is the possible to perform multi-process anomaly detection using side-channels?
 - Is it possible to monitor two distinct software processes executing simultaneously using a single side-channel probe?
 - Assuming we can classify the processes, can we determine which process is running on which processor?

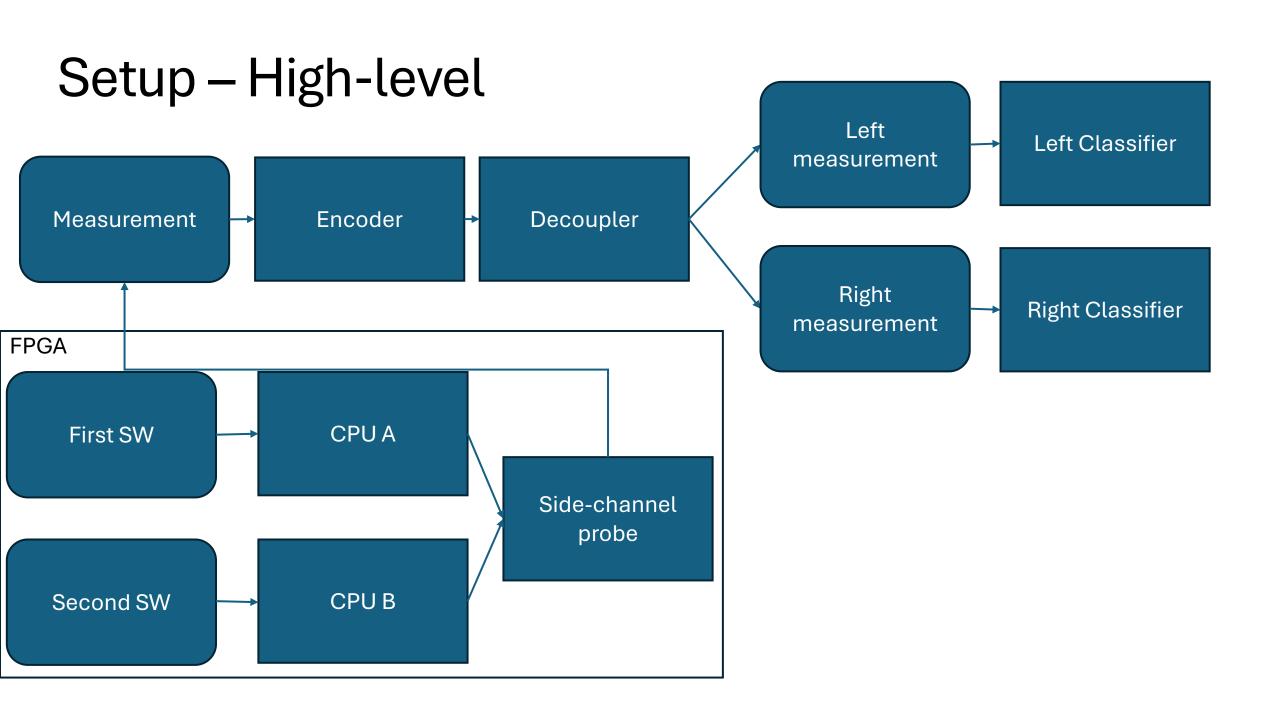


Our contributions

- Our contribution is three-fold:
 - Improving the practicability of multi-process side-channel monitoring
 - Multi-model machine learning solution
 - Evaluation of feasibility in performing side-channel monitoring on multiple, simultaneously executing, software processes.
 - Machine learning-based approach to classify a single side-channel measurement trace as two classes from a set of predefined processes.
 - Wherein the two classes also indicates which of the two cores the process has been executed on.

On a high-level

- Execute simultaneous processes on separate cores
- Power consumption of device measured using single probe
- Use encoder to create latent representation
- Create concept of "left" and "right" measurement
- Classify respective side
- Give classification as input to anomaly detector [out of scope]

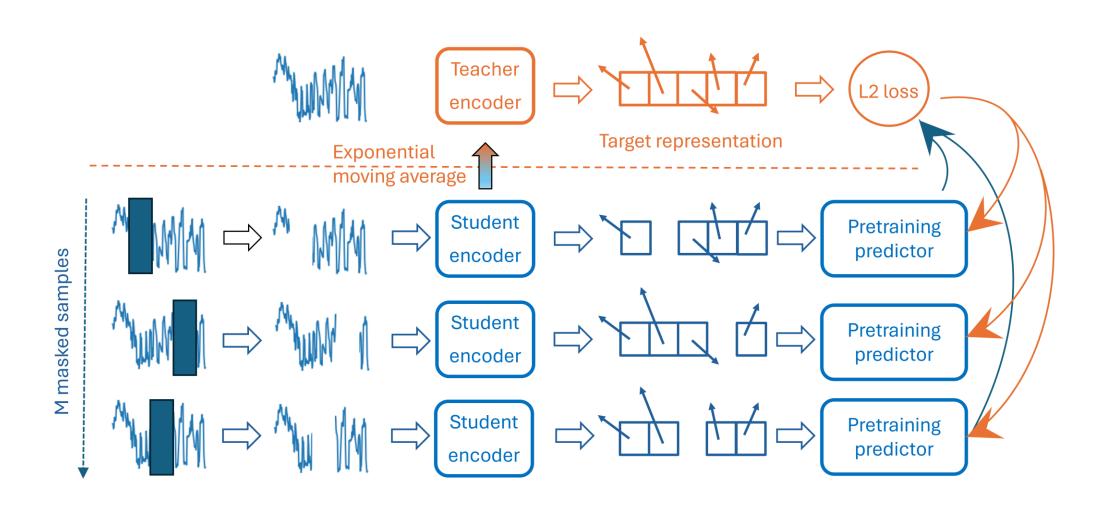


Setup – Machine learning models

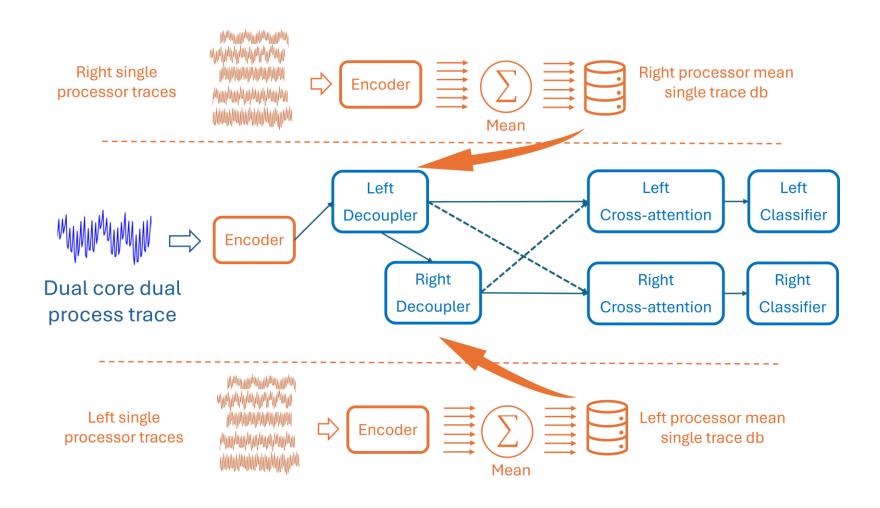
Four blocks:

- Pretrained encoder
 - Separately trained, produce well-suited latent representation of side-channel-trace
- Decoupler
 - Divide the encoded trace into a left and right block
- Cross-attention
 - Mix attention of the left and right block
- Classifier
 - Determine and output two classes, one for left and one for right processor.

Setup – Pre-training encoder



Setup – Machine learning models



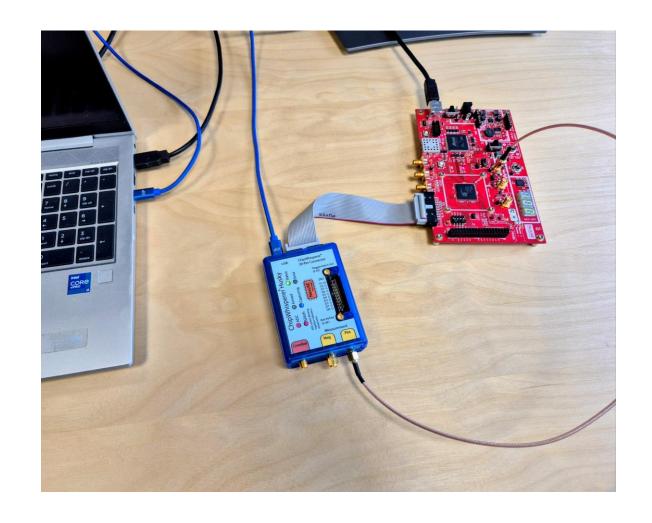
Setup – Attention heads

- Decoupler has one attention head per known process (class)
 - Supervised
 - Learns specific traits for process and class
- Cross-attention has additional attention heads
 - Unsupervised
 - Learns specific dual-core properties



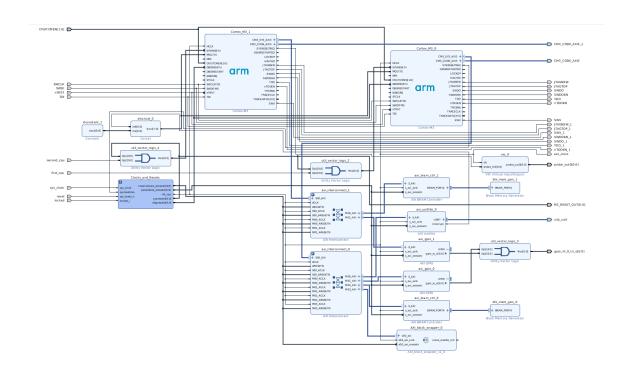
Measurement setup

- Monitor
 - Chipwhisperer Husky + HP Elitebook 850 G8
- Device-under-monitoring
 - CW305 A100 Artix-7 FPGA
 - Pre-soldered resistive shunt on VCC
- Synchronous monitoring
 - 4 samples / clock cycle



Measurement setup (cont.)

- Two soft Cortex-M3 cores, C_A and C_B
 - Clock speed of 20 MHz
 - Separate BRAM blocks
 - Clock generated by monitor
- Measurement trigger
 - Wire triggered from C_A



Scope limitations

- Simple software
 - Evaluated using software from BEEBS*
 - Software without branches, interrupts or varying input
- Process synchronization
 - Simultaneous start of processes
- "Fresh" processor
 - Processors in reset prior to measurement
- Deterministic processors
 - No branch-prediction or speculative execution

^{*} Bristol / Embecosm Embedded Benchmark Suite (https://github.com/mageec/beebs)

Evaluation

- Eleven classes
 - Ten software processes + one category of "no process"
- ~ 1000 samples of 4500 clock cycles per class combination
- 70% used for training
- 10% for validation
- 20% as held-out independent test set

Results

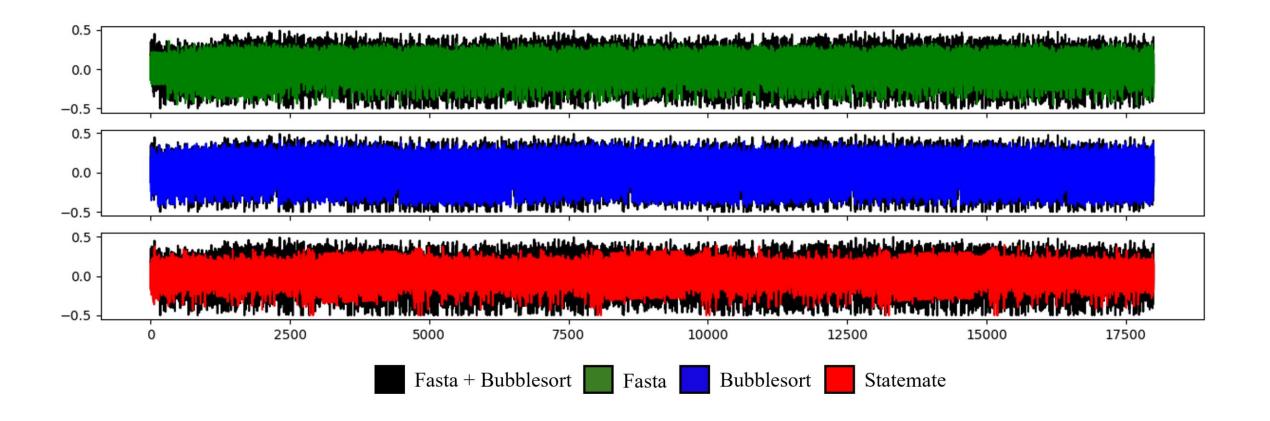
- Five-fold validation
- Average dual correctness –
 94,1%
 - Worst process 85,4%
- Average single correctness –
 97%
 - Worst process 92,7%

TABLE I. DUAL-CORE CLASSIFICATION ACCURACY LISTED BY THE CLASS OF THE PROCESS RUNNING ON $\mathcal{C}_{\mathcal{A}}$.

$\mathcal{C}_{\mathcal{A}}$ class	Accuracy	Single acc.	# Test	# Valid	# Train
cnt	$96.1\% \pm 0.9$	$98.0\% \pm 0.5$	2200	1100	7700
fasta	$91.1\% \pm 1.1$	$95.6\% \pm 0.5$	2000	1000	7000
prime	$97.5\% \pm 0.4$	$98.8\% \pm 0.2$	2200	1100	7700
ahacompress	$95.8\% \pm 4.8$	$97.9\% \pm 2.4$	2200	1100	7700
bubblesort	$97.3\% \pm 4.2$	$98.6\% \pm 2.1$	2200	1100	7700
cover	$98.2\% \pm 4.1$	$99.1\% \pm 2.0$	2200	1100	7700
tarai	$91.9\% \pm 2.0$	$95.9\% \pm 1.0$	2200	1100	7700
lcdnum	$96.3\% \pm 3.6$	$98.2\% \pm 1.8$	2200	1100	7700
crc32	$85.4\% \pm 3.6$	$92.7\% \pm 1.8$	2200	1100	7700
statemate	$96.4\% \pm 5.0$	$98.2\% \pm 2.5$	2200	1100	7700
$idle^a$	$88.5\% \pm 5.0$	$94.2\% \pm 2.5$	2200	1100	7700
Total	$94.1\% \pm 2.2$	$97.0\% \pm 1.1$	24000	12000	84000

^aNo process currently executing on $\mathcal{C}_{\mathcal{A}}$.

Measurements illustrated





Discussion

- Results indicate that dual processes monitoring is feasible
 - Latent representation is key.
 - Can we represent more complex software behavior?
- Oversampling
 - Often not feasible in real-world settings.
 - How would it impact result if we go below Nyquist threshold?
- Processor optimizations
 - Not only software but also processor behavior must be monitored.
 - Can we learn to identify hardware optimization patterns?

Next steps and interesting research directions

- End-to-end anomaly detection
 - Select golden sample from classifier output
- More than two processors
 - What is the noise limit?
- Single process on multiple cores
- What can we represent in latent space?
 - We must evaluate whether we efficiently can determine (or filter out)
 - Hardware optimizations
 - Out-of-order execution
 - Software branches
 - Combine with prior work on side-channels & control flow graphs





https://www.ericsson.com/en/blog/2023/4/side-channel-analysis